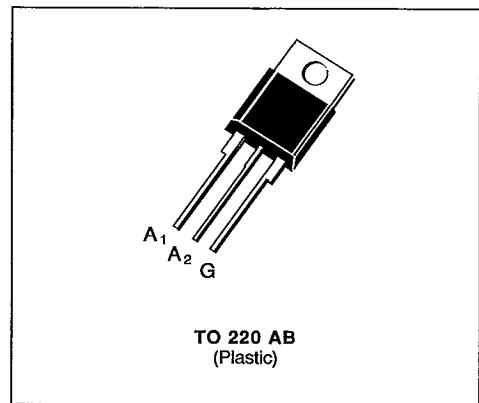


S G S-THOMSON**SENSITIVE GATE TRIACS**

- GLASS PASSIVATED CHIP
- I_{GT} SPECIFIED IN FOUR QUADRANTS
- AVAILABLE IN INSULATED VERSION →
BTA SERIES (INSULATING VOLTAGE
2500 V_{RMS}) OR IN UNINSULATED VERSION
→ BTB SERIES
- UL RECOGNIZED FOR BTA SERIES (E81734)

**DESCRIPTION**

New range suited for applications such as phase control and static switching.

ABSOLUTE RATINGS (limiting values)

Symbol	Parameter	Value	Unit
I_{TRMS}	RMS on-state Current (360° conduction angle)	4	A
I_{TSM}	Non Repetitive Surge Peak on-state Current (T_i initial = 25 °C - Half sine wave)	$t = 8.3$ ms	A
		$t = 10$ ms	
I^2t	I^2t Value for Fusing	12.5	A^2s
di/dt	Critical Rate of Rise of on-state Current (1)	10	$A/\mu s$
		50	
T_{stg} T_j	Storage and Operating Junction Temperature Range	- 40 to 150° - 40 to 110°	°C °C

Symbol	Parameter	BTA/BTB 04-					Unit
		200D	400D	600D	700D	800D	
V_{DRM}	Repetitive Peak off-state Voltage (2)	200	400	600	700	800	V

(1) $I_0 = 100$ mA $di/dt = 1$ A/ μs (2) $T_j = 110$ °C.**THERMAL RESISTANCES**

Symbol	Parameter	Value	Unit
$R_{th (J-a)}$	Junction to Ambient	60	°C/W
$R_{th (J-c)}$ DC	Junction to Case for DC	8.7	°C/W
$R_{th (J-c)}$ AC	Junction to Case for 360 ° Conduction Angle (F = 50 Hz)	6.5	°C/W

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GATE CHARACTERISTICS (maximum values)

$$\begin{array}{ll} P_{GM} = 40 \text{ W } (t_p = 10 \mu\text{s}) & I_{GM} = 4 \text{ A } (t_p = 10 \mu\text{s}) \\ P_G(\text{AV}) = 1 \text{ W} & V_{GM} = 16 \text{ V } (t_p = 10 \mu\text{s}) \end{array}$$

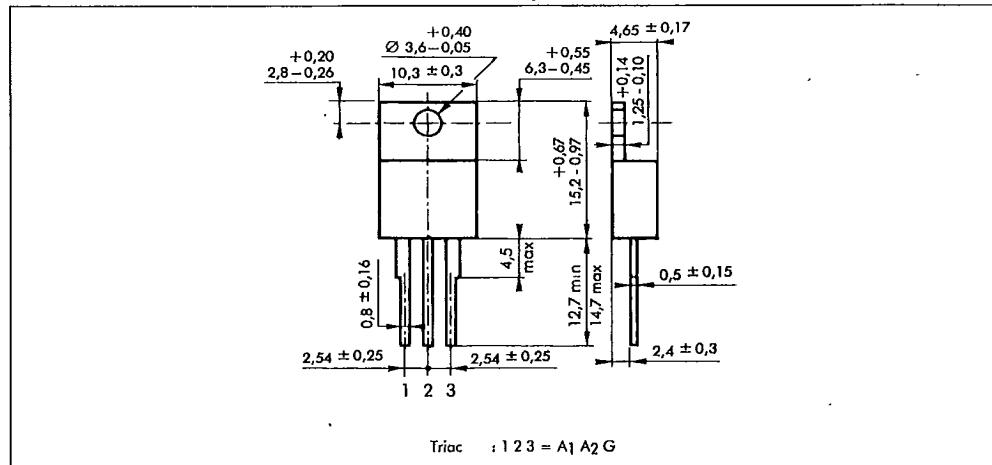
ELECTRICAL CHARACTERISTICS

Symbol	Test Conditions	Quadrants	Min.	Typ.	Max.	Unit
I_{GT}	$T_j = 25^\circ\text{C}$ $V_D = 12 \text{ V}$ $R_L = 33 \Omega$	I-II-III			5	
	Pulse Duration > 20 μs	IV			10	
V_{GT}	$T_j = 25^\circ\text{C}$ $V_D = 12 \text{ V}$ $R_L = 33 \Omega$	I-II-III-IV			1.5	V
V_{GD}	$T_j = 110^\circ\text{C}$ $V_D = V_{DRM}$ $R_L = 3.3 \text{ k}\Omega$	I-II-III-IV	0.2			V
I_H^*	$T_j = 25^\circ\text{C}$ $I_T = 100 \text{ mA}$ Gate Open				15	mA
I_L	$T_j = 25^\circ\text{C}$ $V_D = 12 \text{ V}$ $I_G = 20 \text{ mA}$	I-III-IV		15		mA
	Pulse Duration > 20 μs	II		30		
V_{TM}^*	$T_j = 25^\circ\text{C}$ $I_{TM} = 5.5 \text{ A}$ $t_p = 10 \text{ ms}$				1.65	V
I_{DRM}^*	V_{DRM} Specified	$T_j = 25^\circ\text{C}$			0.01	mA
		$T_j = 110^\circ\text{C}$			0.75	
dv/dt^*	$T_j = 110^\circ\text{C}$ Gate Open Linear Slope up to $V_D = 67\% V_{DRM}$			10		V/ μs
$(dv/dt)_c^*$	$T_C = 75^\circ\text{C}$ $V_D = V_{DRM}$ $I_T = 5.5 \text{ A}$ $(di/dt)_c = 1.8 \text{ A/ms}$			1		V/ μs
t_{gt}	$T_j = 25^\circ\text{C}$ $V_D = V_{DRM}$ $I_T = 5.5 \text{ A}$ $I_G = 20 \text{ mA}$ $di_G/dt = 0.25 \text{ A}/\mu\text{s}$	I-II-III-IV		2		μs

* For either polarity of electrode A₂ voltage with reference to electrode A₁.

PACKAGE MECHANICAL DATA

TO 220 AB Plastic



Cooling method : by conduction (method C)

Marking : type number

Weight : 2 g.

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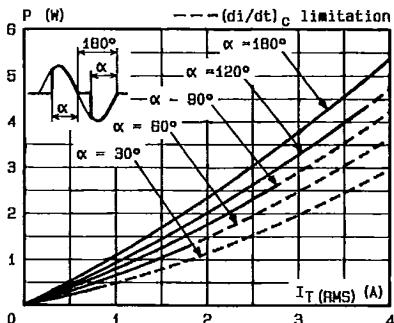
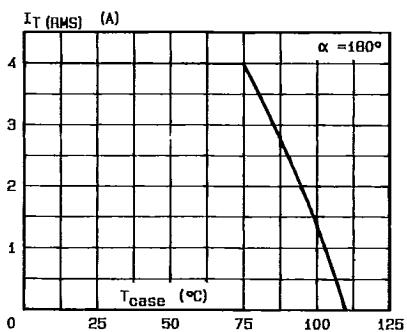
Fig.1 - Maximum mean power dissipation versus RMS on-state current ($f = 60$ Hz).

Fig.3 - RMS on-state current versus case temperature.

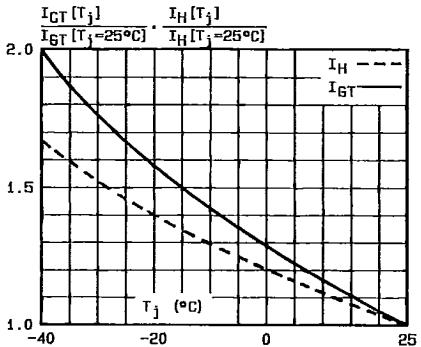


Fig.5 - Relative variation of gate trigger current and holding current versus junction temperature.

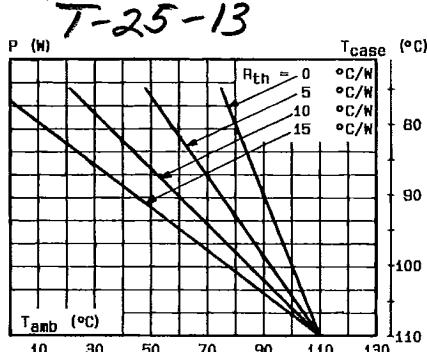
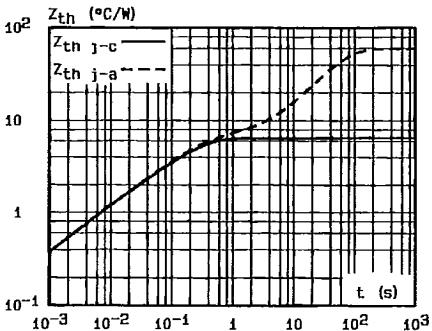
Fig.2 - Correlation between maximum mean power dissipation and maximum allowable temperatures (T_{amb} and T_{case}) for different thermal resistances heatsink + contact.

Fig.4 - Thermal transient impedance junction to case and junction to ambient versus pulse duration.

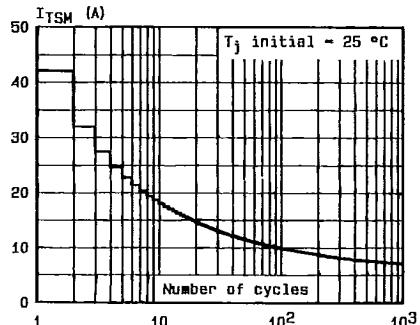


Fig.6 - Non repetitive surge peak on-state current versus number of cycles.

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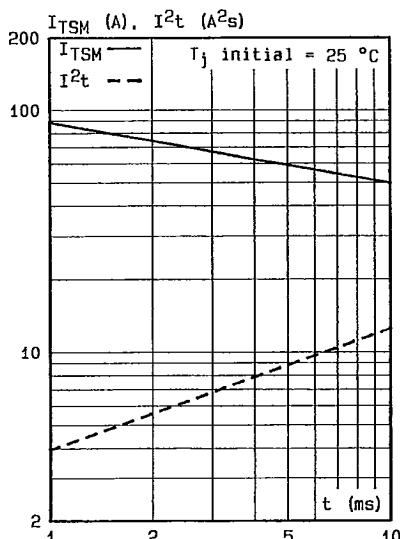


Fig.7 - Non repetitive surge peak on-state current for a sinusoidal pulse with width : $t \leq 10$ ms, and corresponding value of I^2t .

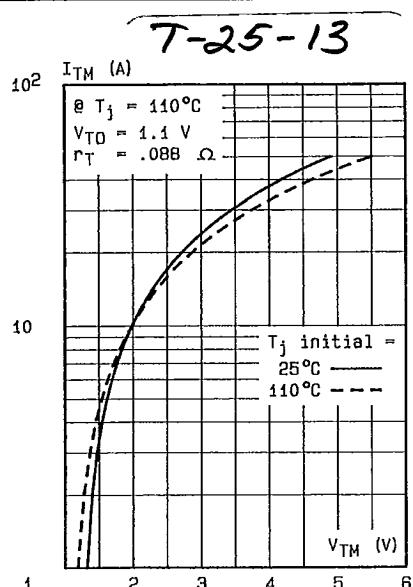


Fig.8 - On-state characteristics (maximum values).